SLOVENSKI STANDARD
oSIST prEN IEC 63567-1:2026

01-februar-2026

Polprevodniški elementi - Vrednotenje učinkovitosti komponent za obdelavo polprevodnikov in opreme za pregledovanje - 1. del: Metoda ocenjevanja prepustnosti pelikule EUV

Semiconductor devices - Performance evaluation of semiconductor processing components and inspection equipment - Part 1: Transmittance evaluation method of EUV pellicle

Ta slovenski standard je istoveten z: **prEN IEC 63567-1:2025**

ICS:

31.080.99	Drugi polprevodniški elementi	Other semiconductor devices

oSIST prEN IEC 63567-1:2026 **en**

47/2976/CDV

COMMITTEE DRAFT FOR VOTE (CDV)

PROJECT NUMBER: **IEC 63567-1 ED1**	
DATE OF CIRCULATION: **2025-12-19**	CLOSING DATE FOR VOTING: **2026-03-13**
SUPERSEDES DOCUMENTS: **47/2860/CD, 47/2935/CC**	

IEC TC 47 : SEMICONDUCTOR DEVICES	
SECRETARIAT: Korea, Republic of	SECRETARY: Mr Cheolung Cha
OF INTEREST TO THE FOLLOWING COMMITTEES:	HORIZONTAL FUNCTION(S):
ASPECTS CONCERNED:	
☒ SUBMITTED FOR CENELEC PARALLEL VOTING **Attention IEC-CENELEC parallel voting** The attention of IEC National Committees, members of CENELEC, is drawn to the fact that this Committee Draft for Vote (CDV) is submitted for parallel voting. The CENELEC members are invited to vote through the CENELEC online voting system.	☐ NOT SUBMITTED FOR CENELEC PARALLEL VOTING

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TITLE:

Semiconductor devices - Performance evaluation of semiconductor processing components and inspection equipment - Part 1: Transmittance evaluation method of EUV pellicle

PROPOSED STABILITY DATE: 2029

NOTE FROM TC/SC OFFICERS: